

STF28N60DM2

N-channel 600 V, 0.13 Ω typ., 21 A MDmesh™ DM2 Power MOSFET in a TO-220FP package

Datasheet - production data

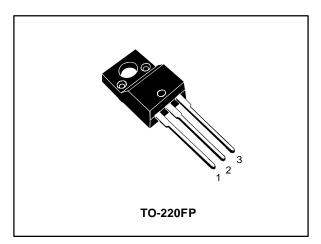
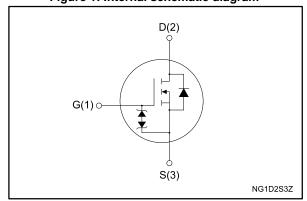


Figure 1: Internal schematic diagram



Features

Order code	V _{DS} @ T _{Jmax} .	R _{DS(on)} max.	I _D	Ртот
STF28N60DM2	650 V	0.16 Ω	21 A	30 W

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

Applications

Switching applications

Description

This high voltage N-channel Power MOSFET is part of the MDmesh™ DM2 fast recovery diode series. It offers very low recovery charge (Q_{rr}) and time (t_{rr}) combined with low R_{DS(on)}, rendering it suitable for the most demanding high efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

Table 1: Device summary

Order code	Marking	Package	Packing
STF28N60DM2	28N60DM2	TO-220FP	Tube

Contents STF28N60DM2

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STF28N60DM2 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _G s	Gate-source voltage	±25	V
1_	Drain current (continuous) at T _{case} = 25 °C	21	Α
l _D	Drain current (continuous) at T _{case} = 100 °C	14	A
I _{DM} ⁽¹⁾	Drain current (pulsed)	84	Α
P _{TOT}	Total dissipation at T _{case} = 25 °C	30	W
dv/dt ⁽²⁾	Peak diode recovery voltage slope	50	V/ns
dv/dt ⁽³⁾	MOSFET dv/dt ruggedness	50	V/IIS
V _{ISO} ⁽⁴⁾	Insulation withstand voltage (RMS) from all three leads to external heat sink	2.5 k	
T _{stg}	Storage temperature	-55 to 150	°C
Tj	Operating junction temperature	-55 10 150	C

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	4.2	°C/W
R _{thj-amb}	Thermal resistance junction-ambient	62.5	C/VV

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR} ⁽¹⁾	Avalanche current, repetitive or not repetitive	4	Α
E _{AS} ⁽²⁾	Single pulse avalanche energy	350	mJ

Notes:

 $^{^{(1)}}$ Pulse width is limited by safe operating area.

 $^{^{(2)}}$ IsD \leq 21 A, di/dt=900 A/µs; VDS peak < V(BR)DSS,VDD = 400 V

 $^{^{(3)}} V_{DS} \le 480 V.$

 $^{^{(4)}}t = 1 \text{ s; Tc} = 25 \text{ °C}$

⁽¹⁾ pulse width limited by T_{jmax}

 $^{^{(2)}}$ starting T_j = 25 °C, I_D = $I_{AR},\,V_{DD}$ = 50 V.

Electrical characteristics STF28N60DM2

2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			>
	I _{DSS} Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			1	
I _{DSS}		$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V},$ $T_{case} = 125 \text{ °C}$			100	μΑ
Igss	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			±10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	3	4	5	٧
R _{DS(on)}	Static drain-source on-resistance	V _{GS} = 10 V, I _D = 10.5 A		0.13	0.16	Ω

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	1500	1	
Coss	Output capacitance	V _{DS} = 100 V, f = 1 MHz,	-	70	ı	pF
Crss	Reverse transfer capacitance	V _G S = 0 V	-	1.6	ı	בֿ
Coss eq. (1)	Equivalent output capacitance	V _{DS} = 0 to 480 V, V _{GS} = 0 V	1	134	ı	рF
R _G	Intrinsic gate resistance	f = 1 MHz, I _D = 0 A	1	4.6	ı	Ω
Qg	Total gate charge	V _{DD} = 480 V, I _D = 21 A, V _{GS} = 10 V (see <i>Figure 15:</i> "Test circuit for gate charge behavior")	-	34	ı	
Q _{gs}	Gate-source charge		-	8	1	nC
Q _{gd}	Gate-drain charge		-	18.5	-	

Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	V _{DD} = 300 V, I _D = 10.5 A	-	16	-	
t _r	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 14: "Test circuit for	ı	7.3	1	
$t_{\text{d(off)}}$	Turn-off delay time	resistive load switching times"	ı	53	ı	ns
t _f	Fall time	and Figure 19: "Switching time waveform")	-	9.3	-	

 $^{^{(1)}}$ Coss eq. is defined as a constant equivalent capacitance giving the same charging time as Coss when VDs increases from 0 to 80% VDSs.

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} ⁽¹⁾	Source-drain current		ı		21	Α
I _{SDM} ⁽²⁾	Source-drain current (pulsed)		1		84	Α
V _{SD} ⁽³⁾	Forward on voltage	V _{GS} = 0 V, I _{SD} = 21 A	ı		1.6	V
t _{rr}	Reverse recovery time	I _{SD} = 21 A, di/dt = 100 A/μs,	1	140		ns
Qrr	Reverse recovery charge	V _{DD} = 60 V (see Figure 16: "Test circuit for inductive load	ı	0.5		μC
I _{RRM}	Reverse recovery current	switching and diode recovery times")	-	7.4		Α
t _{rr}	Reverse recovery time	I _{SD} = 21 A, di/dt = 100 A/µs,	ı	309		ns
Qrr	Reverse recovery charge	V _{DD} = 60 V, T _j = 150 °C (see Figure 16: "Test circuit for inductive load switching and diode recovery times")	1	2.6		μΟ
I _{RRM}	Reverse recovery current		-	16.8		Α

Notes:

Table 9: Gate-source Zener diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 250 \mu\text{A}, I_{D} = 0 \text{A}$	±30	-	-	V

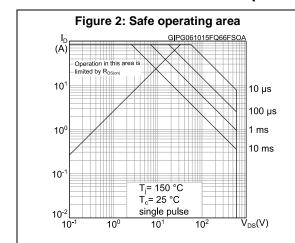
The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.

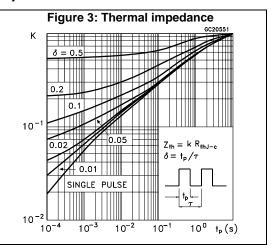
 $^{^{\}left(1\right) }$ Limited by maximum junction temperature.

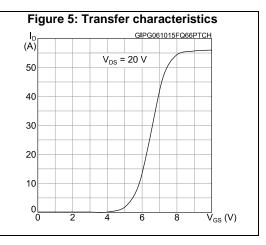
 $^{^{\}left(2\right) }$ Pulse width is limited by safe operating area.

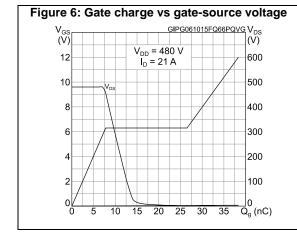
 $^{^{(3)}}$ Pulse test: pulse duration = 300 μ s, duty cycle 1.5%.

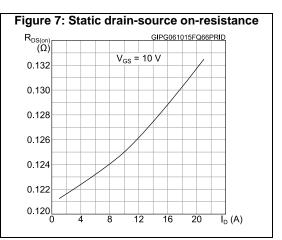
2.1 Electrical characteristics (curves)











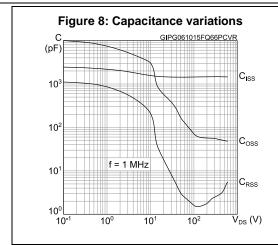


Figure 10: Normalized on-resistance vs temperature

R_{DS(on)} GIPG061015FQ66PRON
(norm.)

2.2

1.8

1.4

1.0

0.6

0.2

-75

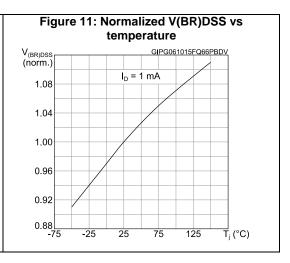
-25

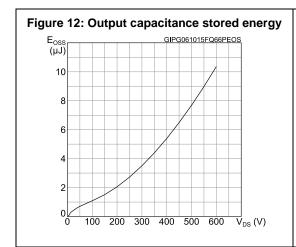
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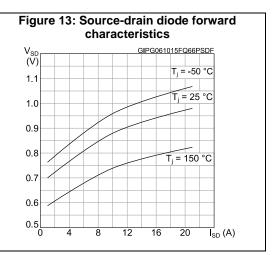
75

125

T_j (°C)







Test circuits STF28N60DM2

3 Test circuits

Figure 14: Test circuit for resistive load switching times

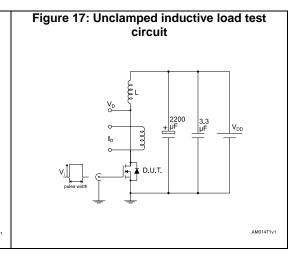
Figure 15: Test circuit for gate charge behavior

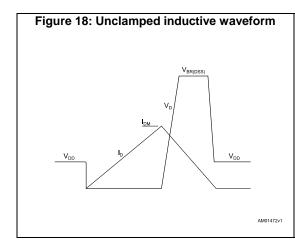
12 V 47 kΩ 100 nF 1 kΩ

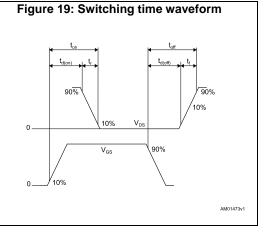
Vos 1 kΩ 1 kΩ

Vos 1 kΩ 1 kΩ

AM01468v1







4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

4.1 TO-220FP package information

Figure 20: TO-220FP package outline Dia L6 L2 *L7* L3 L4 F2 7012510_Rev_K_B

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Table 10: TO-220FP package mechanical data

Dim	·	mm	
Dim.	Min.	Тур.	Max.
A	4.4		4.6
В	2.5		2.7
D	2.5		2.75
Е	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

STF28N60DM2 Revision history

5 Revision history

Table 11: Document revision history

Date	Revision	Changes
04-Sep-2014	1	First release.
09-Oct-2015	2	Text and formatting changes throughout document
		On cover page:
		- upated title and Features table
		In section Electrical ratings:
		- updated all table data
		In section Electrical characteristics:
		- updated all table data
		- renamed table Static (was On /off states)
		- added table Gate-source Zener diode
		Added section Electrical characteristics (curves)
		Updated and renamed section Package mechanical data (was Package information)
		Datasheet promoted from preliminary to production data

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